


<b>Search Notes</b>  	<b>Application/Control No.</b>  10056716	<b>Applicant(s)/Patent Under Reexamination</b>  CHANDRASEKARAN ET AL.
	<b>Examiner</b>  SUSAN Y CHEN	<b>Art Unit</b>  2161

SEARCHED			
Class	Subclass	Date	Examiner
707	all	1/25/2011	tyc
709	all	1/25/2011	tyc
717	all	1/25/2011	tyc
715	all	1/25/2011	tyc
707	all	7/12/2011	tyc
382	all	7/12/2011	tyc

SEARCH NOTES		
Search Notes	Date	Examiner
Palm inventor search	1/25/2011	tyc
NPL-IEEE, Google, ACM	1/25/2011	tyc
West, East DB keywords search	1/25/2011	tyc
NPL-IEEE, Google, ACM	7/12/2011	tyc

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
707	703	1/25/2011	tyc
707	704	1/25/2011	tyc
707	703	7/12/2011	tyc
707	704	7/12/2011	tyc

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